

REMARKS

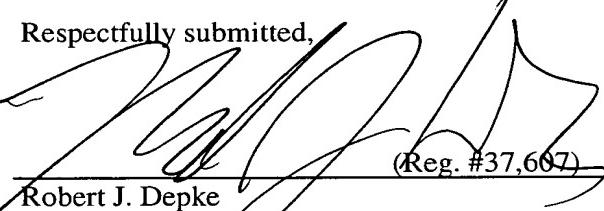
Applicants thank the Examiner for acknowledging receipt of Applicants foreign priority documents that have been submitted pursuant to 35 U.S.C. §119. Applicants have modified the title of the invention in accordance with the Examiners request. Applicants also thank the Examiner for the indication of allowable subject matter in claims 24-49. In light of the foregoing Amendments, Applicants submit that the remaining claims now also stand in condition for allowance.

More specifically, Applicants have modified independent claim 1 to further require that an electric current, voltage or resistance associated with the electrolytic polishing is used in the determination of when the desired thickness has been removed. Applicants respectfully submit that the prior art of record provides no teaching or suggestion whatsoever regarding this advance in the art. More specifically, *Wang* merely describes measuring the optical reflectivity in order to determine when sufficient polishing has been performed. There is simply no teaching nor suggestion whatsoever in *Wang* or any of the other remaining references regarding Applicants improved polishing method, wherein the end point determination for a portion of the overall surface can be more reliably determined in a quick and convenient manner.

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In light of the foregoing, Applicants submit that the application now stands in condition for allowance.

Respectfully submitted,



(Reg. #37,607)

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